

● General Description

The AGM15P30E combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$

This device is ideal for load switch and battery protection applications.

● Features

- Advance high cell density Trench technology
- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance
- 100% Avalanche tested
- 100% DVDS tested

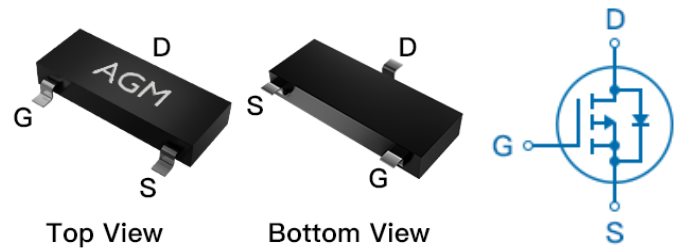
● Application

- MB/VGA Vcore
- SMPS 2nd Synchronous Rectifier
- POL application
- BLDC Motor driver

Product Summary

BVDSS	RDSON	ID
-15V	34mΩ	-4.1A

SOT-23-3 Pin Configuration



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
15P30E	AGM15P30E	SOT-23-3	178mm	8mm	3000

Table 1. Absolute Maximum Ratings (TA=25°C)

Symbol	Parameter	Value	Unit
VDS	Drain-Source Voltage (VGS=0V)	-15	V
VGS	Gate-Source Voltage (VDS=0V)	±10	V
ID	Drain Current-Continuous(Tc=25°C) (Note 1)	-4.1	A
	Drain Current-Continuous(Tc=100°C)	-2.7	A
IDM (pluse)	Drain Current-Pulsed (Note 2)	-16.4	A
PD	Maximum Power Dissipation(Tc=25°C)	1.0	w
	Maximum Power Dissipation(Tc=100°C)	0.4	w
EAS	Avalanche energy (Note 3)	---	mJ
TJ,TSTG	Operating Junction and Storage Temperature Range	-55 To 150	°C

Table 2. Thermal Characteristic

Symbol	Parameter	Typ	Max	Unit
RθJA	Thermal Resistance Junction-ambient (Steady State) ¹	---	125	°C/W

Table 3. Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
On/Off States						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V I _D =-250μA	-15	-18	--	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =-15V, V _{GS} =0V	--	--	-1	μA
IGSS	Gate-Body Leakage Current	V _{GS} =±10V, V _{DS} =0V	--	--	±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250μA	-0.4	-0.6	-1.0	V
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =-3A	--	5	--	S
R _{DS(on)}	Drain-Source On-State Resistance	V _{GS} =-4.5V, I _D =-3.5A	--	34	40	mΩ
		V _{GS} =-2.5V, I _D =-3A	--	45	55	mΩ
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} =-10V, V _{GS} =0V, F=1MHZ	--	661	--	pF
C _{oss}	Output Capacitance		--	304	--	pF
C _{rss}	Reverse Transfer Capacitance		--	268	--	pF
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1.0MHz	--	18	--	Ω
Switching Times						
t _{d(on)}	Turn-on Delay Time	I _D = -3.3A V _{DS} = -10V V _{GS} = -4.5V R _G = 10Ω	--	12	--	nS
t _r	Turn-on Rise Time		--	32	--	nS
t _{d(off)}	Turn-Off Delay Time		--	30	--	nS
t _f	Turn-Off Fall Time		--	11	--	nS
Q _g	Total Gate Charge	V _{GS} =-10V, V _{DS} =-10V, I _D =-3.3A	--	12	--	nC
Q _{gs}	Gate-Source Charge		--	0.7	--	nC
Q _{gd}	Gate-Drain Charge		--	1.6	--	nC
Source-Drain Diode Characteristics						
I _{SD}	Source-Drain Current(Body Diode)		--	--	-4.1	A
V _{SD}	Forward on Voltage	V _{GS} =0V, I _S =-3.5A	--	--	-1.2	V
t _{rr}	Reverse Recovery Time	I _{sd} =-3.5A ,	--	--	--	ns
Q _{rr}	Reverse Recovery Charge	dI/dt=100A/μs , T _J =25°C	--	--	--	nc

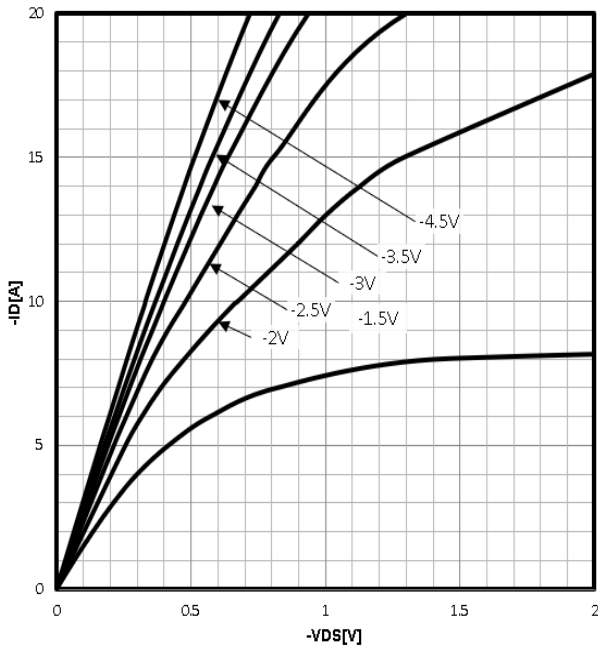
Notes 1.The maximum current rating is package limited.

Notes 2.Repetitive Rating: Pulse width limited by maximum junction temperature

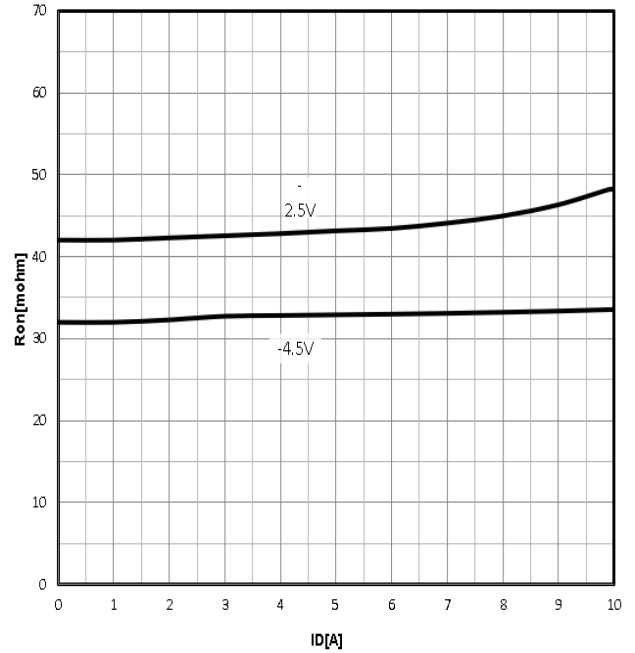
Notes 3.EAS condition: T_J=25°C

Characteristics Curve:

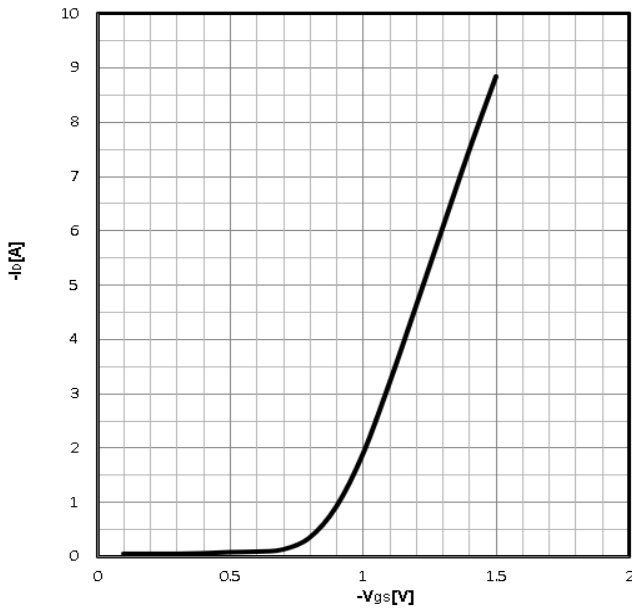
Typ. output characteristics
 $I_D = f(V_{DS})$



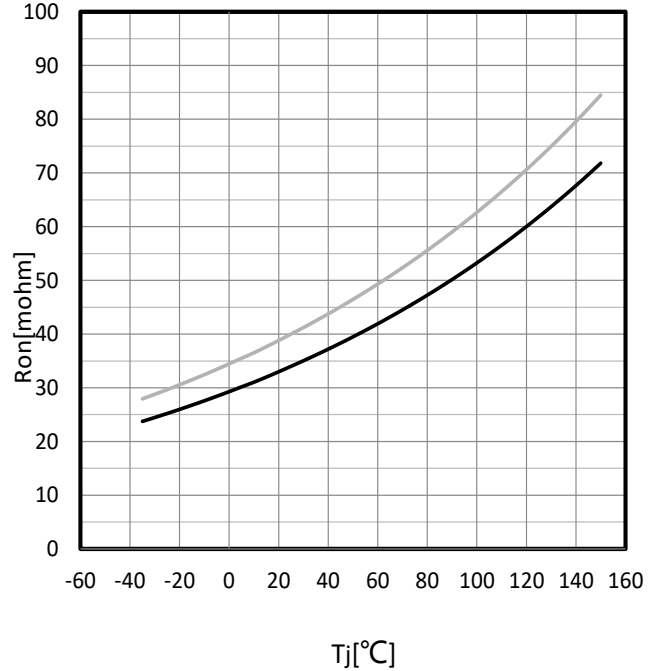
Typ. drain-source on resistance
 $R_{DS(on)} = f(I_D)$



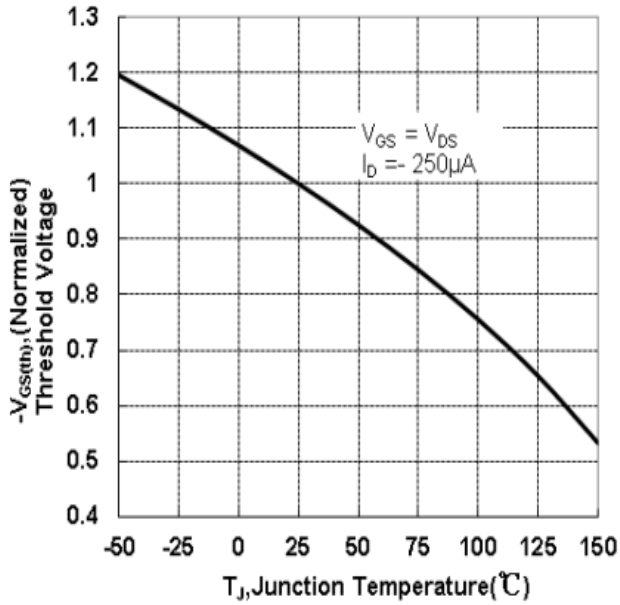
Typ. transfer characteristics
 $I_D = f(V_{GS})$



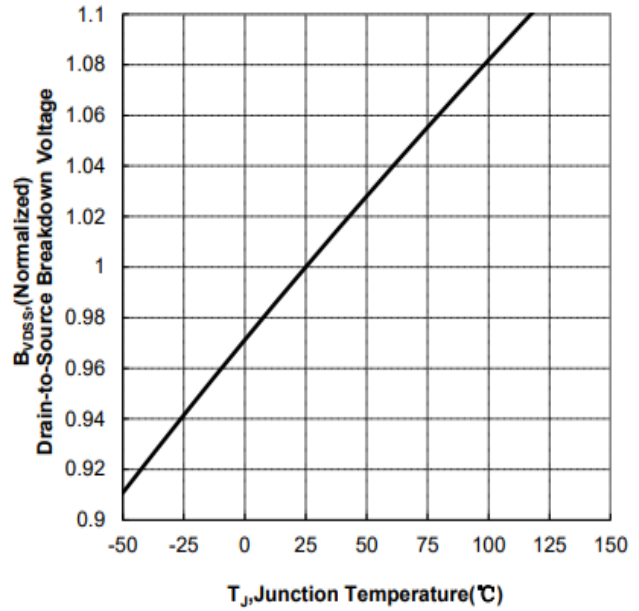
Drain-source on-state resistance
 $R_{DS(on)} = f(T_j); I_D = -3.5A;$



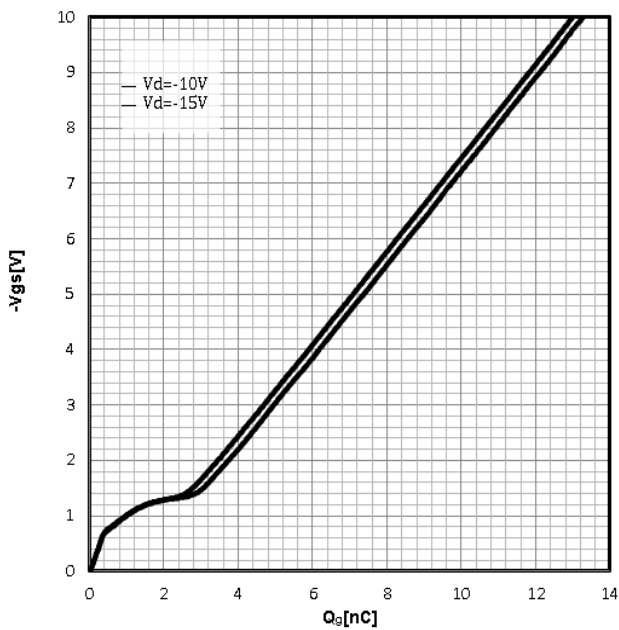
Gate Threshold Voltage
 $-V_{TH}=f(T_j); I_D=-250\mu A$



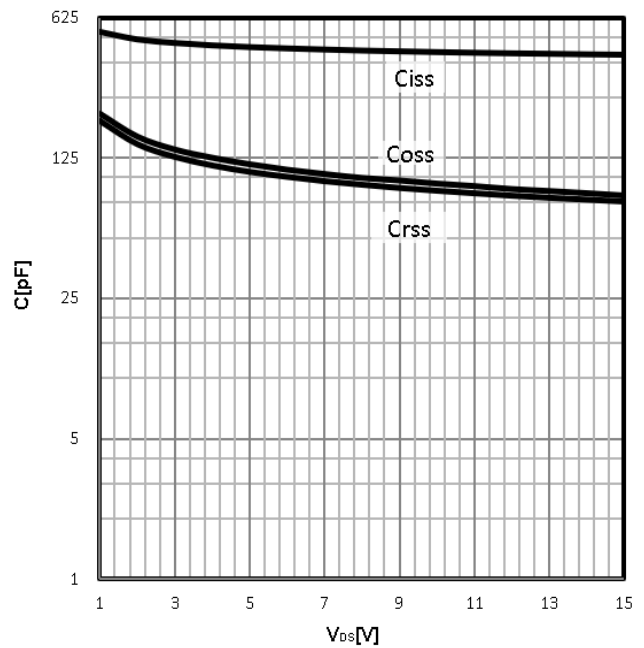
Drain-source breakdown voltage
 $V_{BR(DSS)}=f(T_j); I_D=-250\mu A$



Typ. gate charge
 $V_{GS}=f(Q_g); I_D=-3.3A$

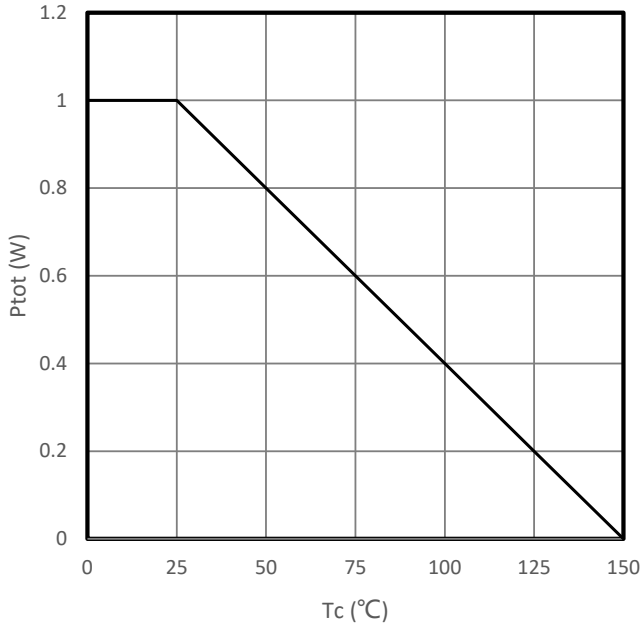


Typ. capacitances
 $C=f(V_{DS}); V_{GS}=0V; f=1MHz$

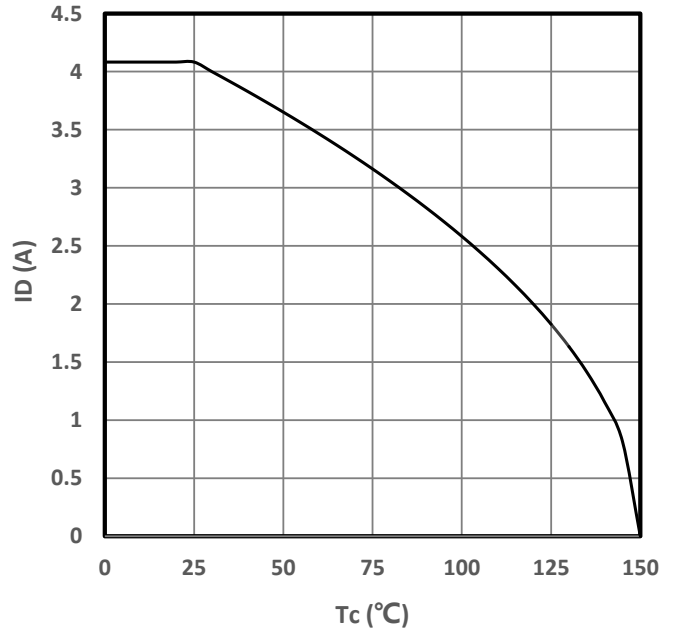


Power Dissipation

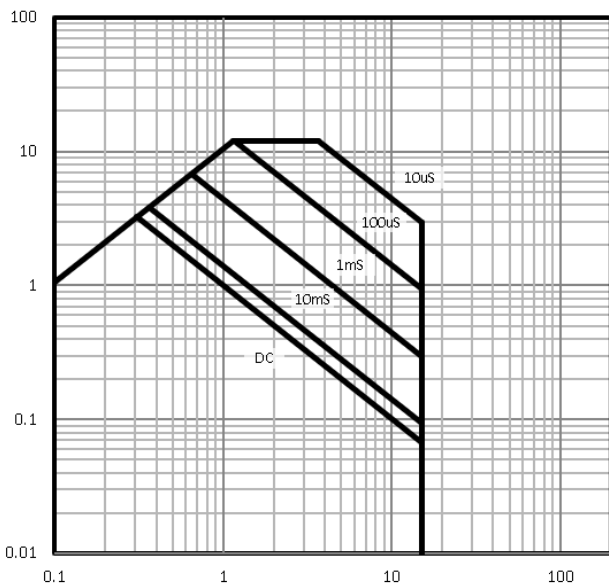
$$P_{tot}=f(T_C)$$


Maximum Drain Current

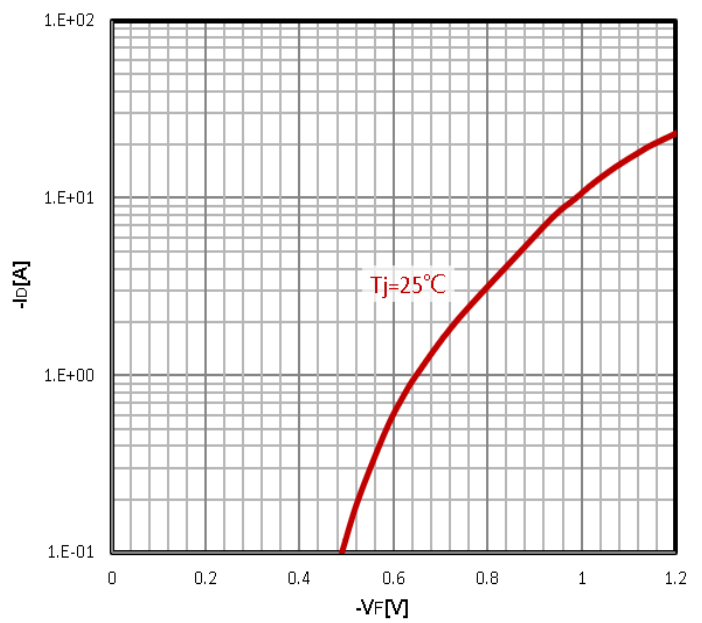
$$-I_D=f(T_C)$$


Safe operating area

$$-I_D=f(-V_{DS})$$

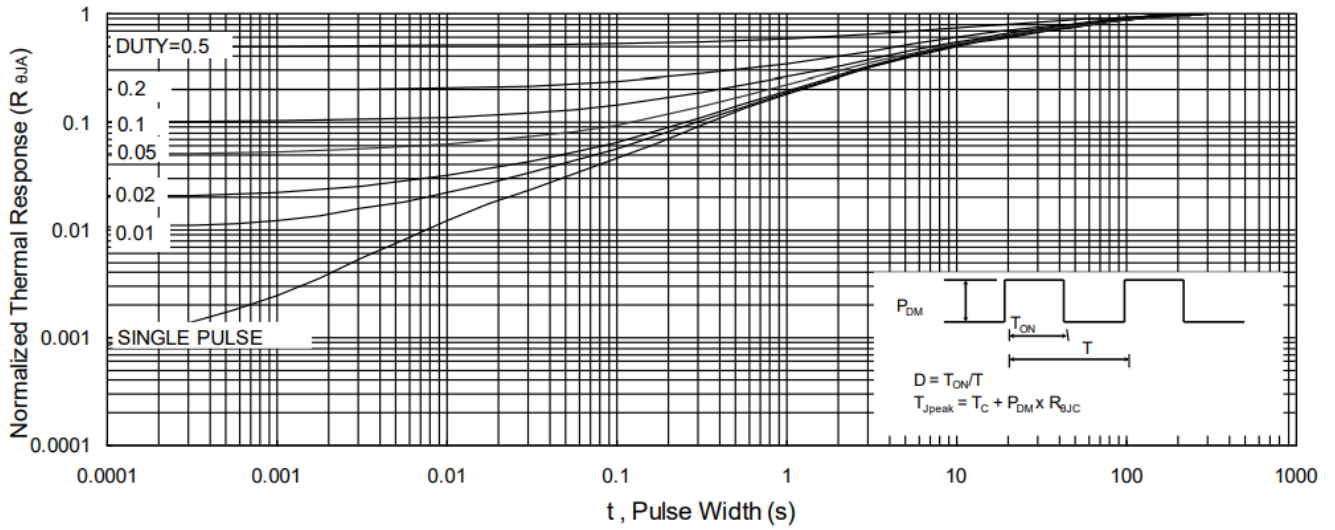

Body Diode Forward Voltage Variation

$$-I_F=f(-V_{GS})$$

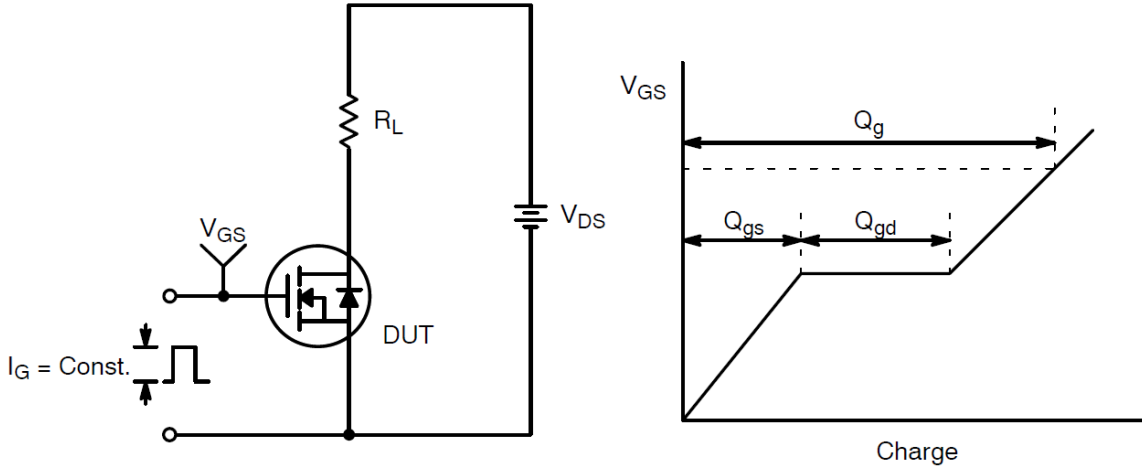


Max. transient thermal impedance

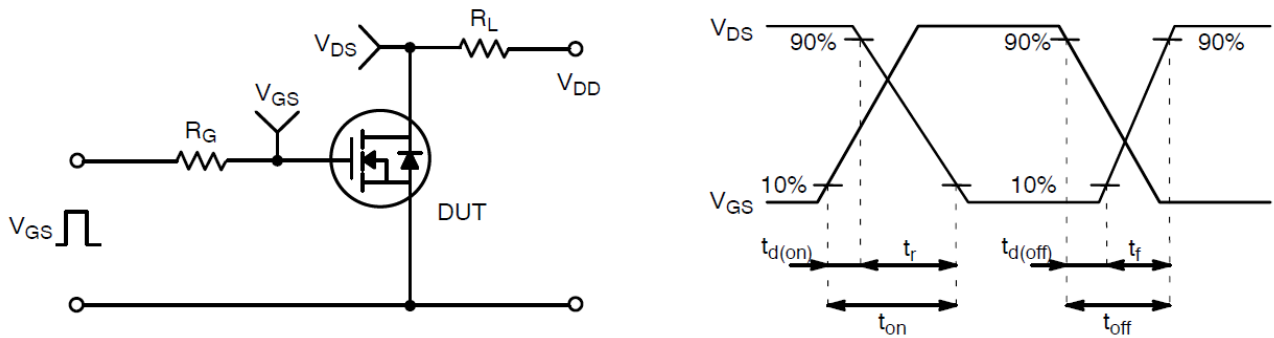
$$Z_{thJC} = f(t_p)$$



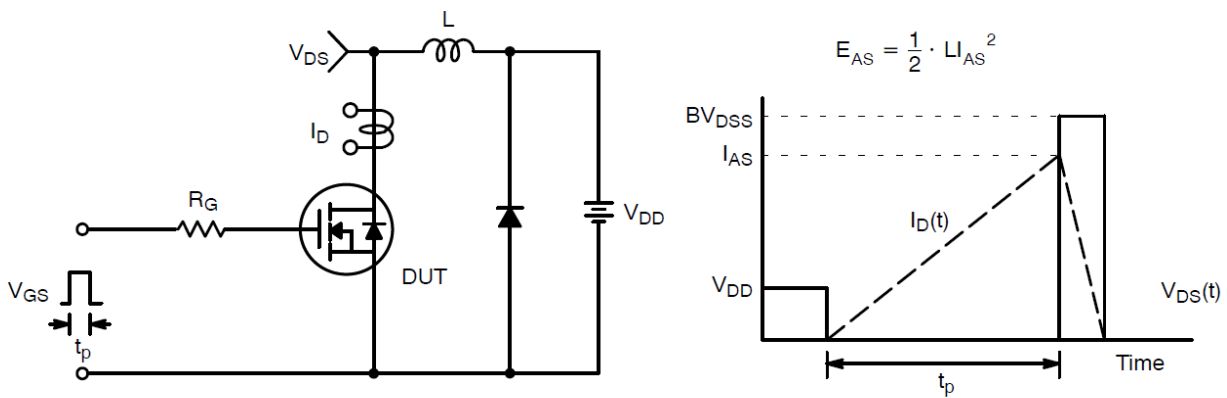
Test Circuit and Waveform:



Gate Charge Test Circuit & Waveform

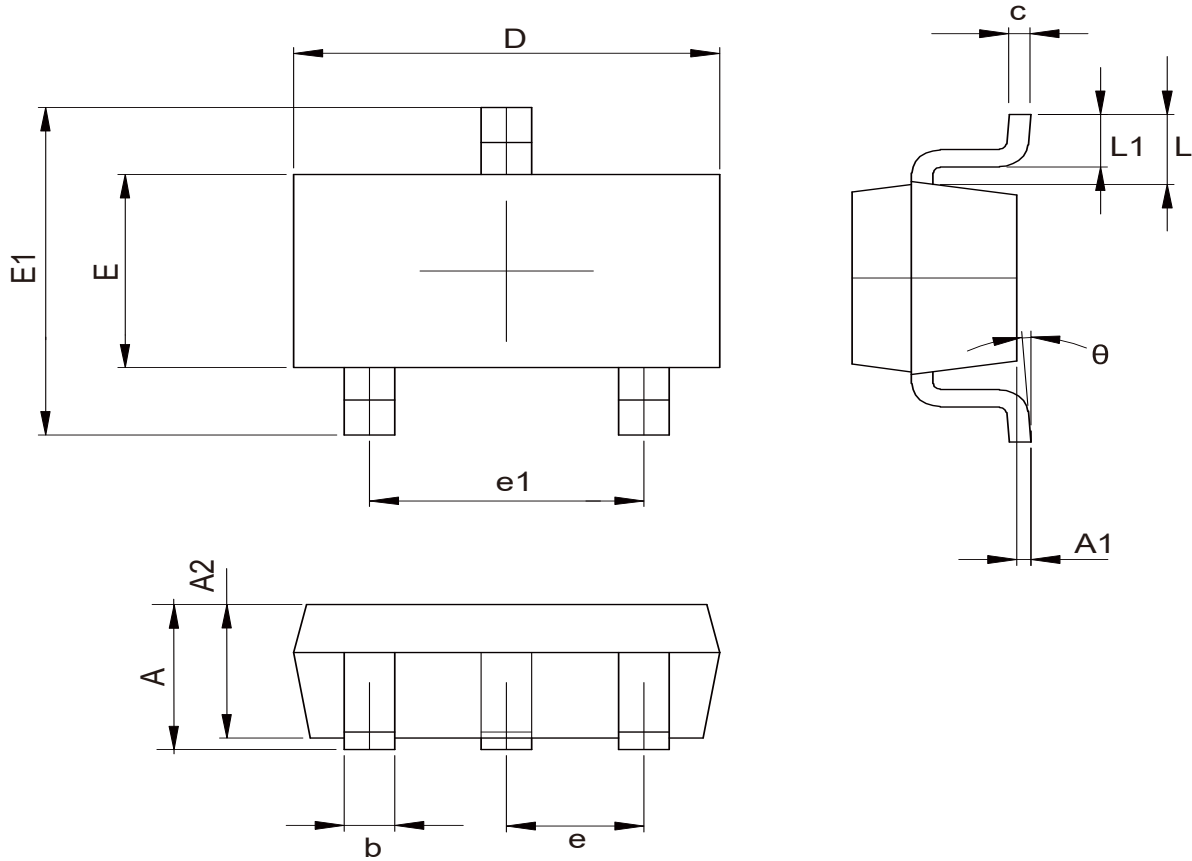


Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

SOT-23-3L
PACKAGE OUTLINE DIMENSIONS



COMMON DIMENSIONS			
CUNITS MEASURE=MILLIMETER			
SYMBOL	MIN	NOM	MAX
A	1.050	---	1.300
A1	0.000	---	0.200
A2	1.050	---	1.200
b	0.300	0.400	0.500
c	0.100	---	0.200
D	2.820	2.900	3.020
E	1.500	1.600	1.700
E1	2.650	2.800	2.950
e	0.950TYP		
e1	1.800	1.900	2.000
L	0.6REF		
L1	0.300	0.450	0.600
θ	0°	--	8°

Unit:mm


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